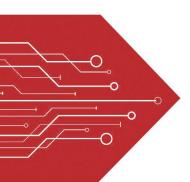
## MSKSEMI















**ESD** 

TVS

TSS

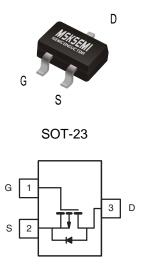
MOV

GDT

**PLED** 

# Broduct data sheet





#### **General Features**

$$\begin{split} &V_{DS}\text{ =-60V,I }_{D}\text{ =-2A} \\ &R_{DS(ON)}\text{ <160m}\Omega\text{ @ }V_{GS}\text{=-10V} \\ &R_{DS(ON)}\text{ <200m}\Omega\text{ @ }V_{GS}\text{=-4.5V} \end{split}$$

#### **Application**

Load switch
PWM application

#### Absolute Maximum Ratings (TA=25<sup>°</sup>C unless otherwise noted)

Symbol	Parameter	Limit	Unit
VDS	Drain-Source Voltage	-60	V
V <sub>G</sub> s	Gate-Source Voltage	±20	V
l <sub>D</sub>	Drain Current-Continuous	-2	А
Ідм	Drain Current-Pulsed (Note 1)	-8	А
P <sub>D</sub>	Maximum Power Dissipation	1.5	W
T <sub>J</sub> ,T <sub>STG</sub>	Operating Junction and Storage Temperature Range	-55 To 150	$^{\circ}$
Reja	Thermal Resistance,Junction-to-Ambient (Note 2)	83.3	°C/W

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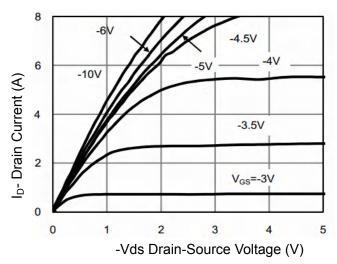
#### Electrical Characteristics (T<sub>C</sub>=25°C unless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit
Off Characteristics			•			
Drain-Source Breakdown Voltage	BV <sub>DSS</sub> V <sub>GS</sub> =0V I <sub>D</sub> =-250μA		-60	-	-	V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =-60V,V <sub>GS</sub> =0V	-	-	-1	μA
Gate-Body Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =±20V,V <sub>DS</sub> =0V	-	-	±100	nA
On Characteristics (Note 3)			•			
Gate Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS}=V_{GS}$ , $I_{D}=-250\mu A$	-1.4	-2.0	-2.6	V
Drain-Source On-State Resistance	-	V <sub>GS</sub> =-10V, I <sub>D</sub> =-1.5A	-	140	160	mΩ
Diain-Source On-State Resistance	R <sub>DS(ON)</sub>	V <sub>GS</sub> =-4.5V, I <sub>D</sub> =-1.5A	-	160	200	mΩ
Forward Transconductance	<b>g</b> FS	V <sub>DS</sub> =-5V,I <sub>D</sub> =-1.5A	-	3	-	S
Dynamic Characteristics (Note4)						
Input Capacitance	C <sub>lss</sub>	\/ - 20\/\/ -0\/	-	444.2	-	PF
Output Capacitance	C <sub>oss</sub>	$V_{DS}$ =-30V, $V_{GS}$ =0V, F=1.0MHz	-	19.6	-	PF
Reverse Transfer Capacitance	C <sub>rss</sub>	F=1.UIVIFIZ	-	17.9	-	PF
Switching Characteristics (Note 4)						
Turn-on Delay Time	t <sub>d(on)</sub>		-	40	-	nS
Turn-on Rise Time	tr	$V_{DD}$ =-30V, $I_{D}$ =-1.5A,	-	35	-	nS
Turn-Off Delay Time	t <sub>d(off)</sub>	$V_{GS}$ =-10 $V$ , $R_{G}$ =3 $\Omega$	-	15	-	nS
Turn-Off Fall Time	t <sub>f</sub>		-	10	-	nS
Total Gate Charge	Qg	V - 20 I - 4 FA	-	11.3	-	nC
Gate-Source Charge	Q <sub>gs</sub>	$V_{DS}$ =-30, $I_{D}$ =-1.5A,	-	2.7	-	nC
Gate-Drain Charge	Q <sub>gd</sub>	V <sub>GS</sub> =-10V	-	1.6	-	nC
Drain-Source Diode Characteristics						
Diode Forward Voltage (Note 3)	V <sub>SD</sub>	V <sub>GS</sub> =0V,I <sub>S</sub> =-1.5A	-		-1.2	V
Diode Forward Current (Note 2)	I <sub>S</sub>		-	-	-1.6	Α
Reverse Recovery Time	t <sub>rr</sub>	T <sub>J</sub> = 25°C, I <sub>F</sub> =- 1.5A	-	25		nS
Reverse Recovery Charge	Qrr	$di/dt = -100A/\mu s^{(Note3)}$	-	31		nC

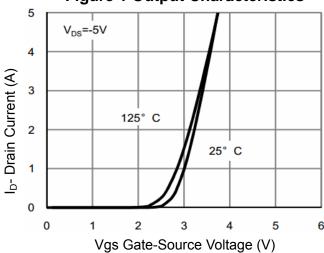
#### Notes:

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- **2.** Surface Mounted on FR4 Board,  $t \le 10$  sec.
- **3.** Pulse Test: Pulse Width ≤  $300\mu$ s, Duty Cycle ≤ 2%.
- 4. Guaranteed by design, not subject to production

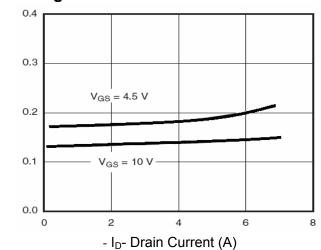
#### **Typical Electrical and Thermal Characteristics (Curves)**



**Figure 1 Output Characteristics** 



**Figure 2 Transfer Characteristics** 



Rdson On-Resistance( ()

Figure 3 Rdson- Drain Current

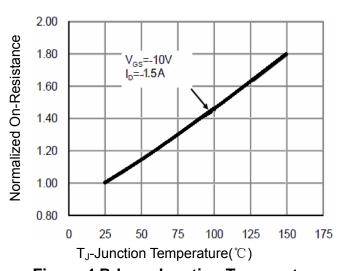
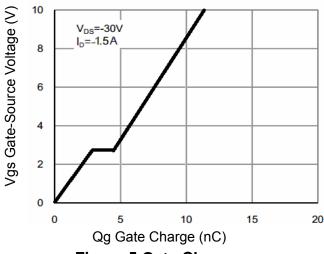


Figure 4 Rdson-Junction Temperature



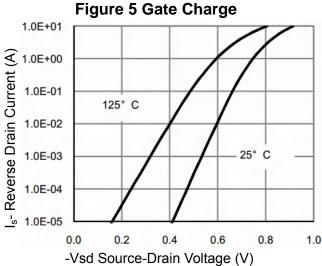


Figure 6 Source- Drain Diode Forward

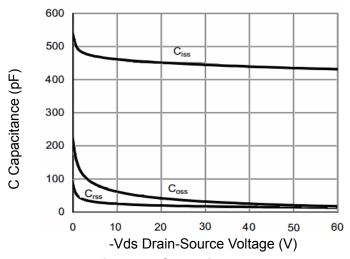
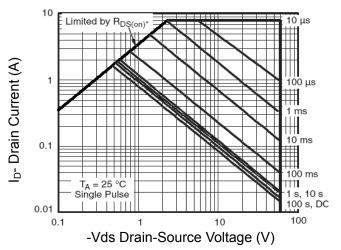


Figure 7 Capacitance vs Vds



**Figure 8 Safe Operation Area** 

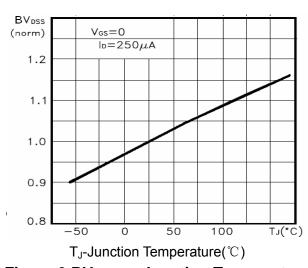


Figure 9 BV<sub>DSS</sub> vs Junction Temperature

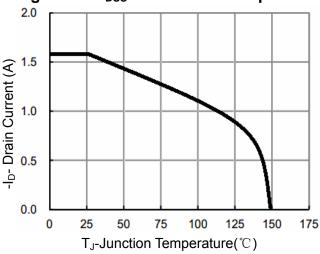
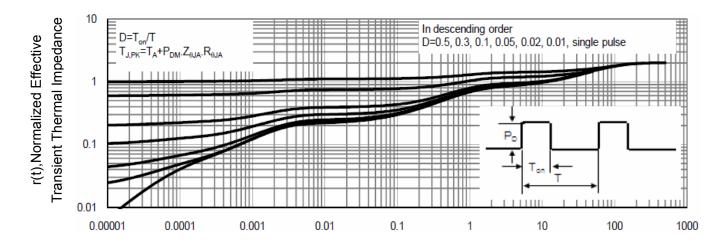


Figure 10 ID Current De-rating

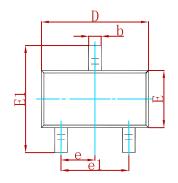


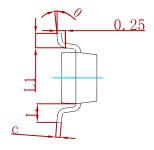
Square Wave Pluse Duration(sec)

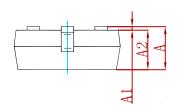
Figure 11 Normalized Maximum Transient Thermal Impedance

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#### **PACKAGE MECHANICAL DATA**

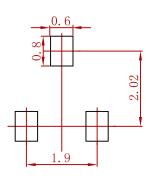






Cumbal	Dimensions In Millimeters		Dimensions In Inches		
Symbol	Min	Max	Min	Max	
Α	0.900	1.150	0.035	0.045	
A1	0.000	0.100	0.000	0.004	
A2	0.900	1.050	0.035	0.041	
b	0.300	0.500	0.012	0.020	
С	0.080	0.150	0.003	0.006	
D	2.800	3.000	0.110	0.118	
E	1.200	1.400	0.047	0.055	
E1	2.250	2.550	0.089	0.100	
е	0.950	) TYP	0.037	7 TYP	
e1	1.800	2.000	0.071	0.079	
L	0.550 REF		0.022 REF		
L1	0.300	0.500	0.012	0.020	
θ	0°	8°	0°	8°	

### **Suggested Pad Layout**



- 1.Controlling dimension:in millimeters.2.General tolerance:± 0.05mm.3.The pad layout is for reference purposes only.

#### **REEL SPECIFICATION**

P/N	PKG	QTY
SI2309CDS-T1-MS	SOT-23	3000



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